Welcome to Galaxy Examinator reports

Date: Tue Sep 3 11:52:58 2024
Product :
LotID :

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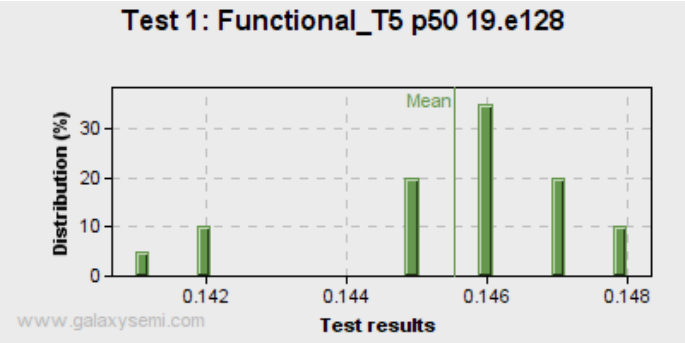
Tests Statistics

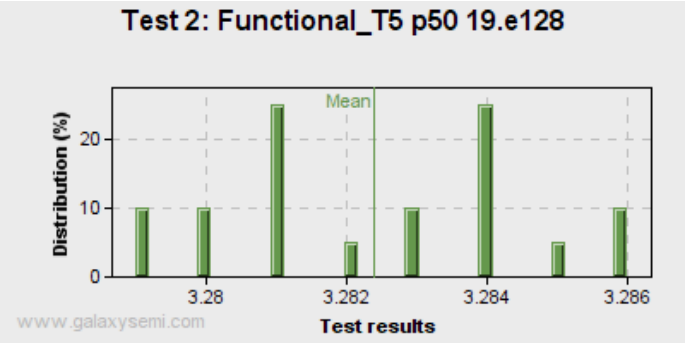
Test	Name	Type	Low L.	High L.	Source	Execs	Fails	Mean	Sigma	Cp	Cpk	Yield
1	Functional_T5 p50 19.e128	P	n/a .	n/a .	Samples	20	0	0.14555	0.00190498	n/a .	n/a .	100.00 %
2	Functional_T5 p50 19.e128	P	n/a .	n/a .	Samples	20	0	3.2824	0.00218608	n/a .	n/a .	100.00 %
4	Functional_T6 p50 19.e128	P	150 ns	350 ns	Samples	20	0	234.4 ns	1.66702 ns	20.00	16.88	100.00 %
5	Functional_T6 p50 19.e128	P	150 ns	350 ns	Samples	20	0	244.5 ns	1.7014 ns	19.59	18.51	100.00 %
6	Functional_T6 A8 0	P	1 ns	100 ns	Samples	20	0	10.1 ns	2.63379 ns	6.26	1.15	100.00 %
7	Functional_T7 p53 19.e135	P	n/a .	n/a .	Samples	20	0	3.2821 V	0.0020494 V	n/a .	n/a .	100.00 %
8	Functional_T7 p53 19.e135	P	n/a .	n/a .	Samples	20	0	0.1392	0.00230788	n/a .	n/a .	100.00 %
12	Functional_T8 A8 0	P	1 ns	20 ns	Samples	20	2	154.76 ns	662.175 ns	0.0048	−0.0678	90.00 %
786000	Soft_Bin parameter	–	n/a .	n/a .	Samples	20	0	1	0	n/a .	n/a .	100.00 %
786001	Hard_Bin parameter	–	n/a .	n/a .	Samples	20	0	1	0	n/a .	n/a .	100.00 %
786002	Die_X parameter	–	n/a .	n/a .	Samples	20	0	1.5	1.14708	n/a .	n/a .	100.00 %
786003	Die_Y parameter	–	n/a .	n/a .	Samples	20	0	2	1.45095	n/a .	n/a .	100.00 %
786004	Test_Time parameter	–	0.0 sec	n/a .	Samples	20	0	2.43565 sec	0.44072 sec	n/a .	1.84	100.00 %
786006	Testing_Site parameter	–	n/a .	n/a .	Samples	20	0	0	0	n/a .	n/a .	100.00 %
786007	Part_ID parameter	–	n/a .	n/a .	Samples	20	0	10.5	5.91608	n/a .	n/a .	100.00 %

Histogram of Tests

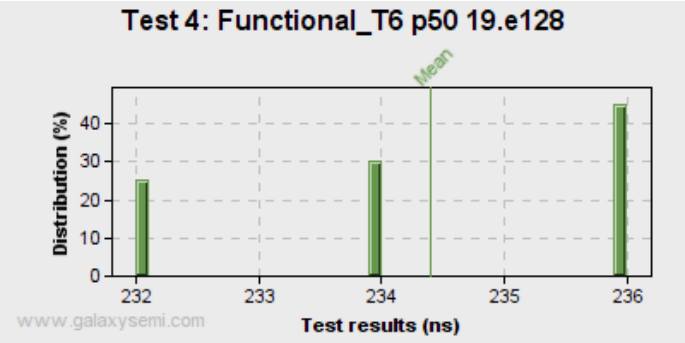
Test	1
Name	Functional_T5 p50 19.e128
Test type	Parametric
Low limit	n/a .
High limit	n/a .
Exec / Fails	20 / 0 (0.00%)
Mean	0.14555
Sigma	0.00190498
Range	0.007
Cp / Cpk	n/a . / n/a .
Samples	20



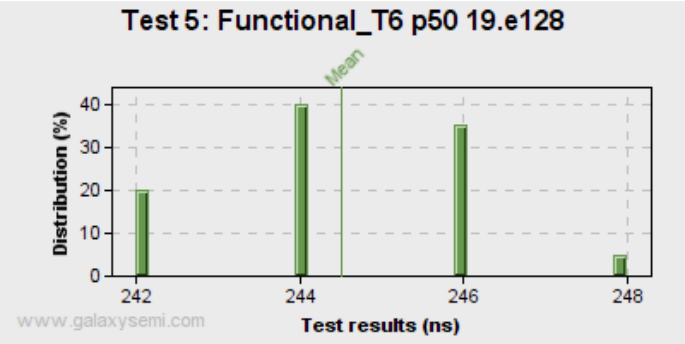
Test	2
Name	Functional_T5 p50 19.e128
Test type	Parametric
Low limit	n/a .
High limit	n/a .
Exec / Fails	20 / 0 (0.00%)
Mean	3.2824
Sigma	0.00218608
Range	0.00699997
Cp / Cpk	n/a . / n/a .
Samples	20



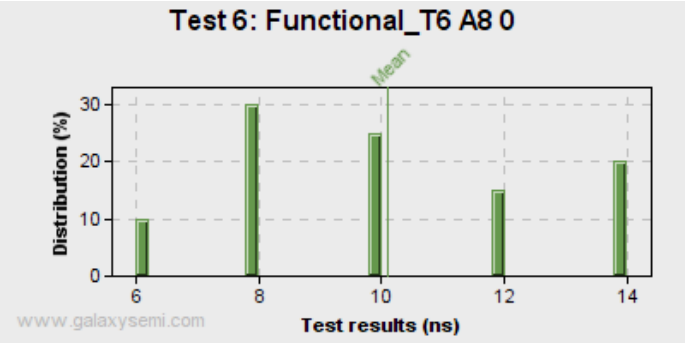
Test	4
Name	Functional_T6 p50 19.e128
Test type	Parametric
Low limit	150 ns
High limit	350 ns
Exec / Fails	20 / 0 (0.00%)
Mean	234.4 ns
Sigma	1.66702 ns
Range	4 ns
Cp / Cpk	20.00 / 16.88
Samples	20



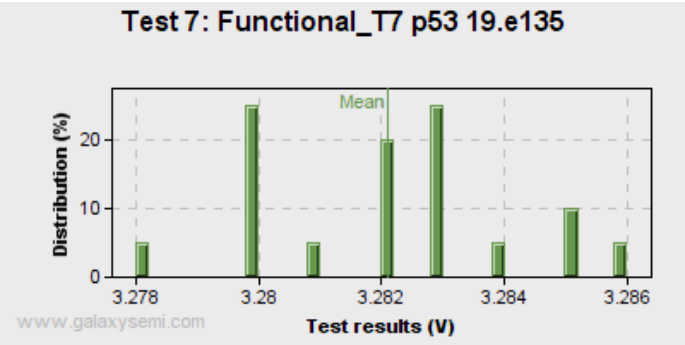
Test	5
Name	Functional_T6 p50 19.e128
Test type	Parametric
Low limit	150 ns
High limit	350 ns
Exec / Fails	20 / 0 (0.00%)
Mean	244.5 ns
Sigma	1.7014 ns
Range	5.99999 ns
Cp / Cpk	19.59 / 18.51
Samples	20



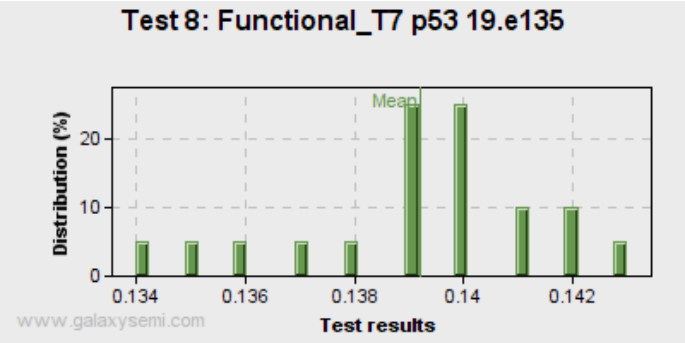
Test	6
Name	Functional_T6 A8 0
Test type	Parametric
Low limit	1 ns
High limit	100 ns
Exec / Fails	20 / 0 (0.00%)
Mean	10.1 ns
Sigma	2.63379 ns
Range	8 ns
Cp / Cpk	6.26 / 1.15
Samples	20



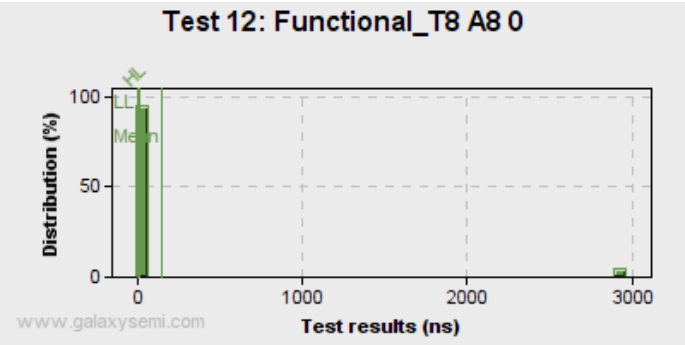
Test	7
Name	Functional_T7 p53 19.e135
Test type	Parametric
Low limit	n/a .
High limit	n/a .
Exec / Fails	20 / 0 (0.00%)
Mean	3.2821 V
Sigma	0.0020494 V
Range	0.0079999 V
Cp / Cpk	n/a . / n/a .
Samples	20



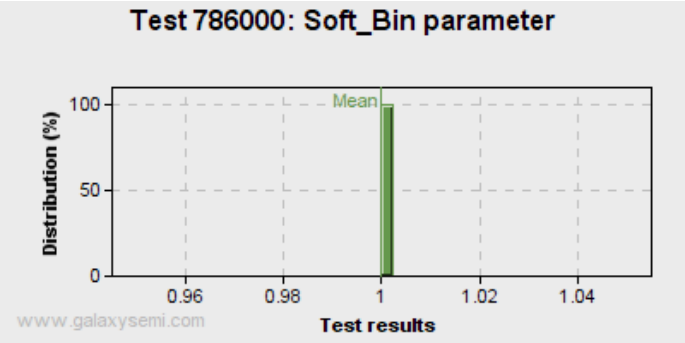
Test	8
Name	Functional_T7 p53 19.e135
Test type	Parametric
Low limit	n/a .
High limit	n/a .
Exec / Fails	20 / 0 (0.00%)
Mean	0.1392
Sigma	0.00230788
Range	0.009
Cp / Cpk	n/a . / n/a .
Samples	20



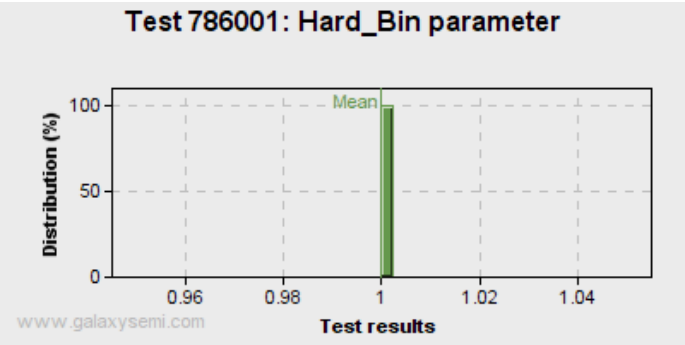
Test	12
Name	Functional_T8 A8 0
Test type	Parametric
Low limit	1 ns
High limit	20 ns
Exec / Fails	20 / 2 (10.00%)
Mean	**154.76 ns**
Sigma	662.175 ns
Range	2970 ns
Cp / Cpk	0.0048 / −0.0678 ....=&gt Warning: Process is over the high limit
Samples	20



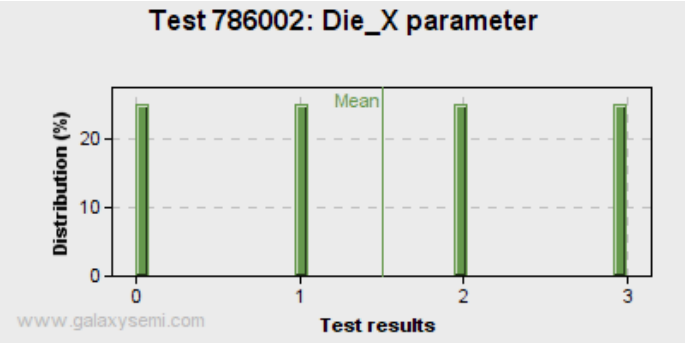
Test	786000
Name	Soft_Bin parameter
Test type	–
Low limit	n/a .
High limit	n/a .
Exec / Fails	20 / 0 (0.00%)
Mean	1
Sigma	0
Range	0
Cp / Cpk	n/a . / n/a .
Samples	20



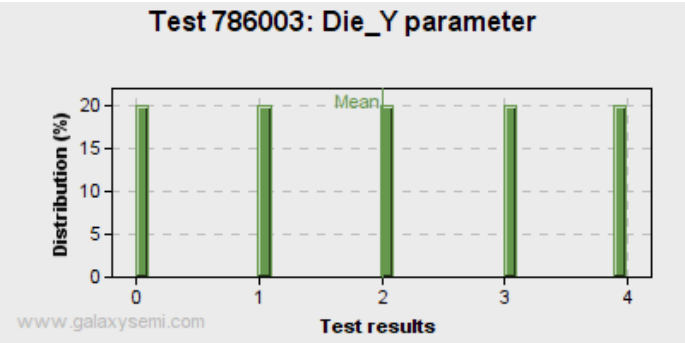
Test	786001
Name	Hard_Bin parameter
Test type	–
Low limit	n/a .
High limit	n/a .
Exec / Fails	20 / 0 (0.00%)
Mean	1
Sigma	0
Range	0
Cp / Cpk	n/a . / n/a .
Samples	20



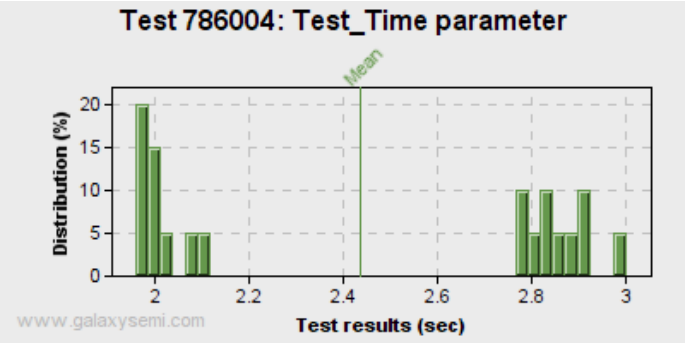
Test	786002
Name	Die_X parameter
Test type	–
Low limit	n/a .
High limit	n/a .
Exec / Fails	20 / 0 (0.00%)
Mean	1.5
Sigma	1.14708
Range	3
Cp / Cpk	n/a . / n/a .
Samples	20



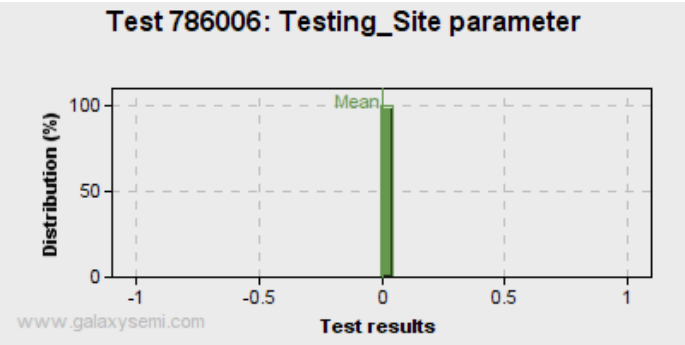
Test	786003
Name	Die_Y parameter
Test type	–
Low limit	n/a .
High limit	n/a .
Exec / Fails	20 / 0 (0.00%)
Mean	2
Sigma	1.45095
Range	4
Cp / Cpk	n/a . / n/a .
Samples	20



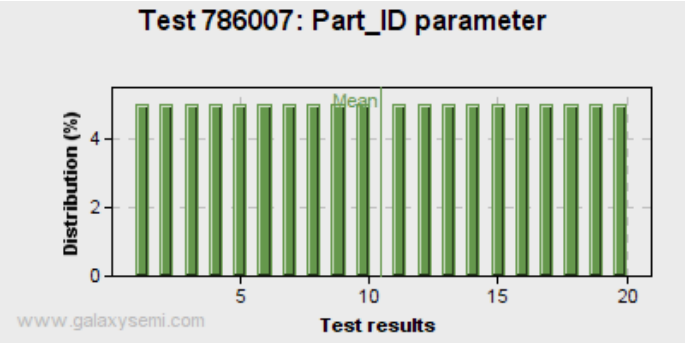
Test	786004
Name	Test_Time parameter
Test type	–
Low limit	0.0 sec
High limit	n/a .
Exec / Fails	20 / 0 (0.00%)
Mean	2.43565 sec
Sigma	0.44072 sec
Range	1.041 sec
Cp / Cpk	n/a . / 1.84
Samples	20



Test	786006
Name	Testing_Site parameter
Test type	–
Low limit	n/a .
High limit	n/a .
Exec / Fails	20 / 0 (0.00%)
Mean	0
Sigma	0
Range	0
Cp / Cpk	n/a . / n/a .
Samples	20



Test	786007
Name	Part_ID parameter
Test type	–
Low limit	n/a .
High limit	n/a .
Exec / Fails	20 / 0 (0.00%)
Mean	10.5
Sigma	5.91608
Range	19
Cp / Cpk	n/a . / n/a .
Samples	20



Pareto of Tests Cp

Test	Name	Cp	Test Cp Chart
12	Functional_T8 A8 0	0.0048	

Shows all Cp <= 1.7 (Defined in Options , section 'Pareto/Define Cp cut−off limit')

Pareto of Tests Cpk

Test	Name	Cpk	Test Cpk Chart
12	Functional_T8 A8 0	−0.0678	
6	Functional_T6 A8 0	1.15	

Shows all Cpk <= 1.3 (Defined in Options , section 'Pareto/Define Cp cut−off limit')

Pareto of Tests failures

Test	Name	Failing Bin	Failures count	Yield Loss	Fail contribution	Test Fail rate	Failures Chart
12	Functional_T8 A8 0	–	2	10.0 %	n/a	10.0 %	
–	**Cumul. of failures**	–	**2**	**10.0 %**	**0.0 %**	**10.0 %**	

-– Yield loss: number of failed test executions / number of parts
-– Fail contribution: number of failed test executions / number of parts failed
-– Test Fail rate: number of failed test executions / number of test executions

Pareto of Functional Failure Signatures (pins tested in parallel)

Total devices tested: **20**
Total patterns detected: **1**

Fail count	% of failures	% of tested	Functional Failure signatures (tested pins failing together)
2	100.00 %	10.00 %	Functional_T8 A8 0 (Test 12)
2	**100 %**	**–**	**Total failures detected**

Shows first 25 % of the failure signatures (Defined in Options, section 'Pareto/Define Failure Signatures cut−off limit')

Pareto of Parametric Failure Signatures (tests failing concurrently)

No Parametric failure signature detected

Pareto of Software Bins

Software Binning	Bin Name	Count	Percentage	Software Binning Chart
1	–	20	100.0 %	
Cumul.	Cumul.	20	100.0%	

Pareto of Hardware Bins

Hardware Binning	Bin Name	Count	Percentage	Hardware Binning Chart
1	–	20	100.0 %	
Cumul.	Cumul.	20	100.0%	

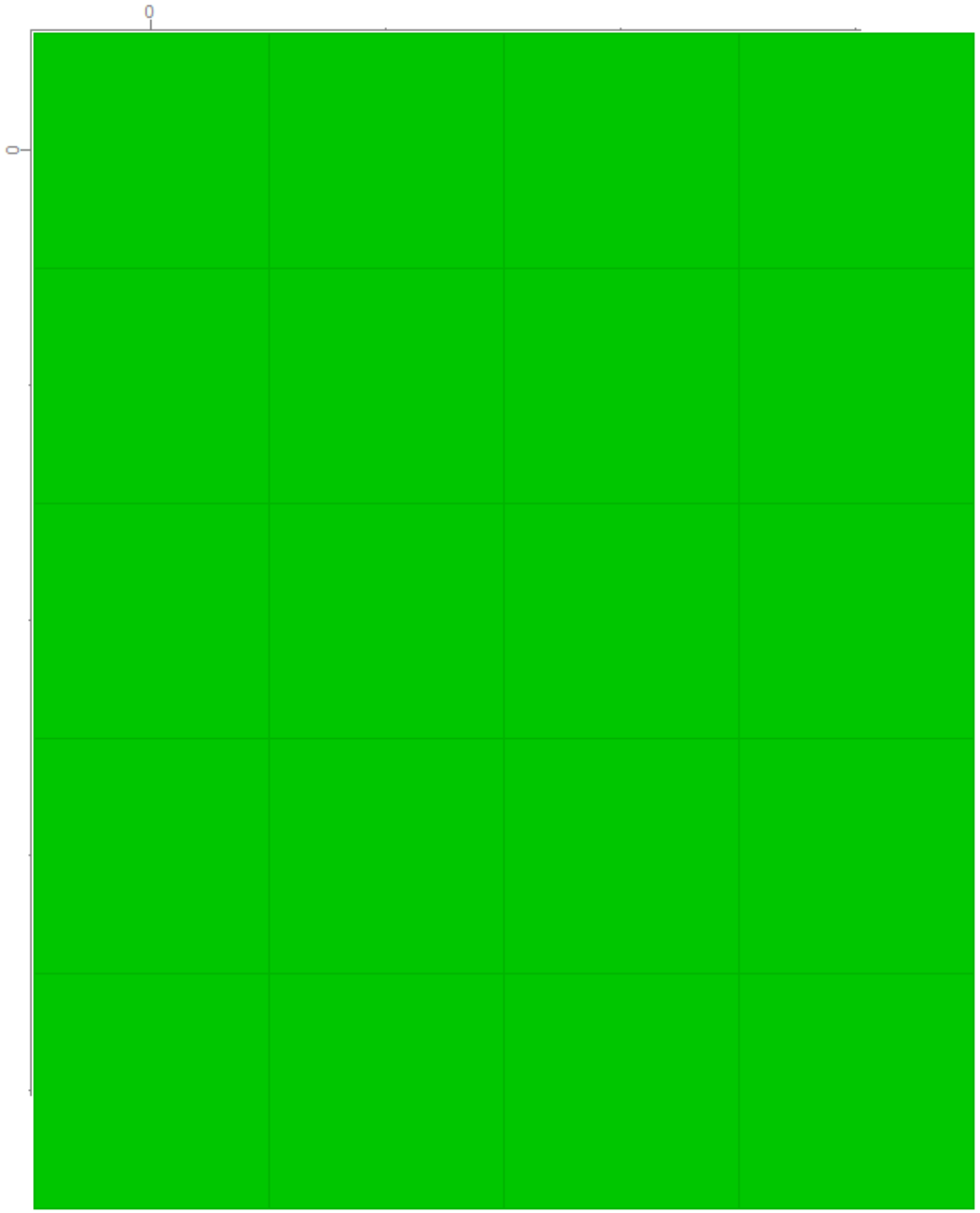
Wafermaps & Strip Maps

Map type	Show Software bins
Devices tested (with retests)	20
Total physical parts tested	20 (only applies to Wafermaps)

List of Individual Maps

Top 10 Software Binning	1
Color	
Pass/Fail	P
Percentage	100.0%
Total count	20

Map style	STRIP map (parts tested are PACKAGED DEVICES!)
Total physical parts tested	20
Parts processed	All Data / parts (any Bin)
Data from Sites	All sites
Strip started	Tue Sep 03 23:41:58 2024
Strip ended	Tue Sep 03 23:48:18 2024
Wafer tested in	6 minutes 20 seconds
Average device test time	19.000 sec.
Map dimensions	LowX=0, LowY=0, HighX=3, HighY=4


0
0

Run 1, Run 2,...

Software Binning Summary

Software Binning	Bin Name	Pass/ Fail	Total count	Percentage	Software Binning Chart
1	–	P	20	100.0 %	
All PASS Bins	**All PASS Bins**	P	**20**	**100.0 %**	
ALL Bins	**ALL Bins**	–	**20**	**100.0 %**	

Hint: From the 'Options' tab in the 'Binning' section, you can configure how to compute the binning (from summary or samples)

Hardware Binning Summary

Hardware Binning	Bin Name	Pass/ Fail	Total count	Percentage	Hardware Binning Chart
1	–	P	20	100.0 %	
All PASS Bins	All PASS Bins	P	20	100.0 %	
ALL Bins	ALL Bins	–	20	100.0 %	

Hint: From the 'Options' tab in the 'Binning' section, you can configure how to compute the binning (from summary or samples)

Message Log

No log message to report

Global Information

Report from	Teradyne–Examinator–Pro+ – V8.1.5 – www.galaxysemi.com
Report created	Tue Sep 03 11:52:58 2024
Data processed	30.4 KB (31127 bytes)
Processing time	0.56 second
Processing speed	54.8 KB/sec
Examinator expires	Sun Sep 3 2034
(null)	–
File name	C:/Users/rahmana/OneDrive – Teradyne/Desktop/New Hire/New Hire Tech/UFP New Hire Train/Project 1/i8243/results_v1_30loop.std
Tests mapping file	n/a

Setup time	Tue Sep 03 23:36:42 2024
Start time	Tue Sep 03 23:41:58 2024
End time	Tue Sep 03 23:48:18 2024
Test duration	6 minutes 20 seconds
Product	n/a
Program	rahmana_i8243_p1.igxl
Revision	n/a
Lot	n/a
Sub−Lot	n/a
WaferID	n/a
Parts processed	All Data / parts (any Bin)
Data from Sites	All sites
Test time (GOOD parts)	2.436 sec. (excludes tester idle time)
Test time (ALL parts)	2.436 sec. (excludes tester idle time)
Average test time	19.000 sec. / device (includes tester idle time between parts)
Total parts tested	20 − Includes parts retested (if any)
Good parts (Yield)	20 (100.00%) − Includes parts retested (if any)
Bad parts (Yield loss)	0 (0.00%) − Includes parts retested (if any)
Parts retested	n/a .
Parts aborted	0 (0.00%)
(null)	−
STDF Version	4.0
Tester name	SNG−UFP−789
Tester type	UltraFLEXplus
Station	1
Part type	n/a
Operator	rahmana
Exec_type	IG−XL
Exec_version	10.30.10_uflx (P1.11)
TestCode	n/a
Test Temperature	n/a
User Text	n/a
Aux_file	n/a
Package type	n/a
Per_freq	n/a
Spec_name	n/a
Spec_version	n/a
Family ID	n/a

Date code	n/a
Design Rev	n/a
Facility ID	n/a
Floor ID	n/a
Proc ID	n/a
Flow ID	n/a
Setup ID	n/a
Eng ID	n/a
ROM code	n/a
Serial #	n/a
Super user name	n/a
Handler/Prober	n/a
(null)	–
Site details	Site# 0

Global Options

Test# policy	Never merge tests with identical test number if test name not matching
Data Cleaning	None (keep all data)
Statistics computation	From samples data (if any), otherwise from summary
Binning computation	From summary data (if any), otherwise from samples
Cp,Cpk computation	Use standard Sigma formula
Mean drift formula	Percentage of value drift